



**ALPHA & OMEGA**  
SEMICONDUCTOR



## AOT462

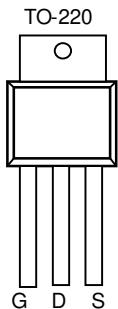
### N-Channel Enhancement Mode Field Effect Transistor

#### General Description

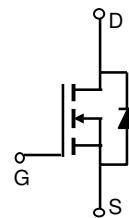
The AOT462 uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. This device is suitable for use in UPS, high current switching applications. *Standard Product AOT462 is Pb-free (meets ROHS & Sony 259 specifications).*

#### Features

$V_{DS}$  (V) = 60V  
 $I_D$  = 70A      ( $V_{GS}$  = 10V)  
 $R_{DS(ON)}$  < 18mΩ      ( $V_{GS}$  = 10V)



Top View  
Drain Connected  
to Tab



#### Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	60	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>G</sup>	$I_D$	70	A
$T_C=100^\circ\text{C}$	$I_D$	70	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	120	
Avalanche Current <sup>C</sup>	$I_{AR}$	26	A
Repetitive avalanche energy $L=0.3\text{mH}$ <sup>C</sup>	$E_{AR}$	101	mJ
Power Dissipation <sup>B</sup>	$P_D$	100	W
$T_C=25^\circ\text{C}$	$P_D$	50	
Junction and Storage Temperature Range	$T_J$ , $T_{STG}$	-55 to 175	°C

#### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	45	60	°C/W
Maximum Junction-to-Case <sup>B</sup>	$R_{\theta JC}$	1.25	1.5	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}$ , $V_{GS}=0\text{V}$	60			V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=60\text{V}$ , $V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1 5	$\mu\text{A}$
$I_{GSS}$	Gate-Body leakage current	$V_{DS}=0\text{V}$ , $V_{GS}=\pm 20\text{V}$			100	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_D=250\mu\text{A}$	2	3.1	4	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=10\text{V}$ , $V_{DS}=5\text{V}$	120			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}$ , $I_D=30\text{A}$ $T_J=125^\circ\text{C}$		14.5 25	18 30	$\text{m}\Omega$
$g_{FS}$	Transconductance	$V_{DS}=5\text{V}$ , $I_D=30\text{A}$		50		S
$V_{SD}$	Diode Forward Voltage	$I_S=1\text{A}$ , $V_{GS}=0\text{V}$		0.73	1	V
$I_S$	Maximum Body-Diode Continuous Current <sup>G</sup>				70	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}$ , $V_{DS}=30\text{V}$ , $f=1\text{MHz}$		1840	2400	pF
$C_{oss}$	Output Capacitance			185		pF
$C_{rss}$	Reverse Transfer Capacitance			80		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}$ , $V_{DS}=0\text{V}$ , $f=1\text{MHz}$		2.8	4.2	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}$ , $V_{DS}=30\text{V}$ , $I_D=30\text{A}$		27.8	36	nC
$Q_{gs}$	Gate Source Charge			9.9		nC
$Q_{gd}$	Gate Drain Charge			6.6		nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=10\text{V}$ , $V_{DS}=30\text{V}$ , $R_L=1\Omega$ , $R_{\text{GEN}}=3\Omega$		12		ns
$t_r$	Turn-On Rise Time			5.2		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			38		ns
$t_f$	Turn-Off Fall Time			27		ns
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F=30\text{A}$ , $dI/dt=100\text{A}/\mu\text{s}$		35	64	ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F=30\text{A}$ , $dI/dt=100\text{A}/\mu\text{s}$		47		nC

A: The value of  $R_{\text{QJA}}$  is measured with the device in a still air environment with  $T_A=25^\circ\text{C}$ .

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=175^\circ\text{C}$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C: Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=175^\circ\text{C}$ .

D. The  $R_{\text{QJA}}$  is the sum of the thermal impedance from junction to case  $R_{\text{QJC}}$  and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using  $<300\ \mu\text{s}$  pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=175^\circ\text{C}$ .

G. The maximum current rating is limited by bond-wires.

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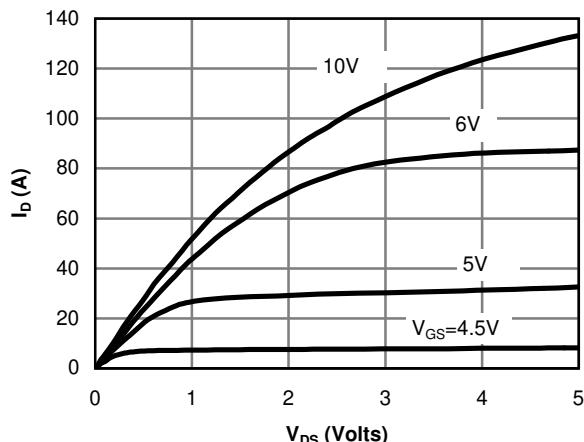
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


Figure 1: On-Region Characteristics

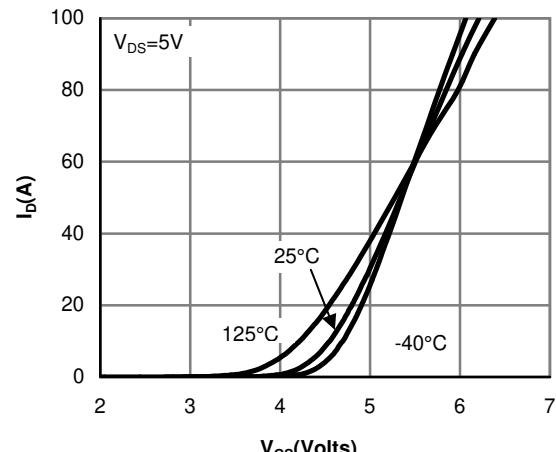


Figure 2: Transfer Characteristics

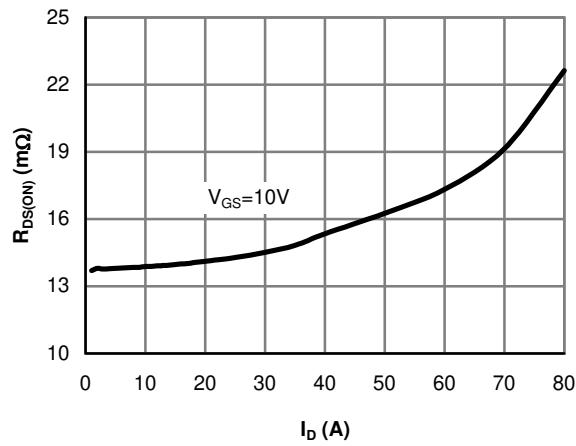


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

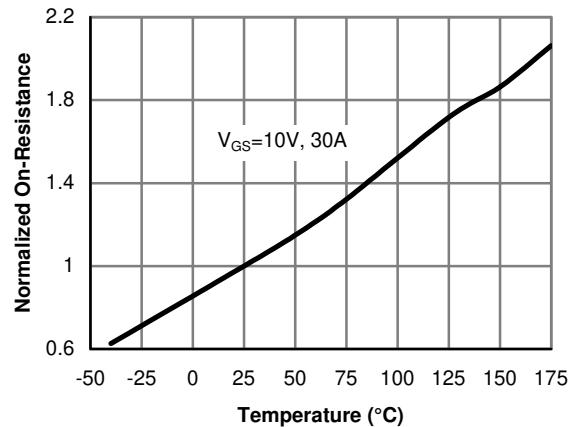


Figure 4: On-Resistance vs. Junction Temperature

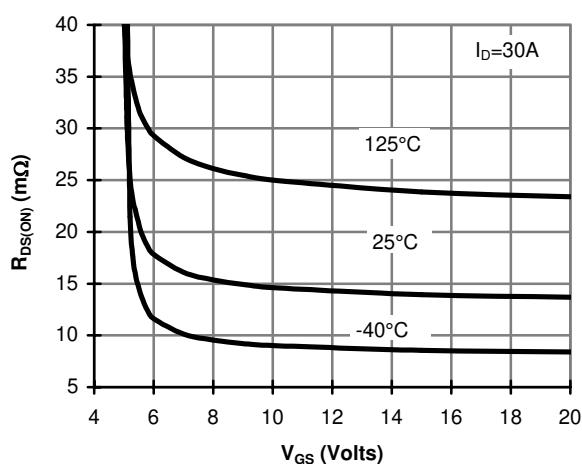


Figure 5: On-Resistance vs. Gate-Source Voltage

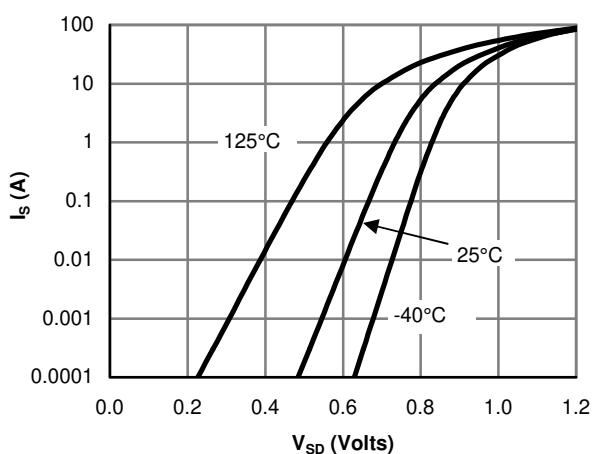


Figure 6: Body-Diode Characteristics

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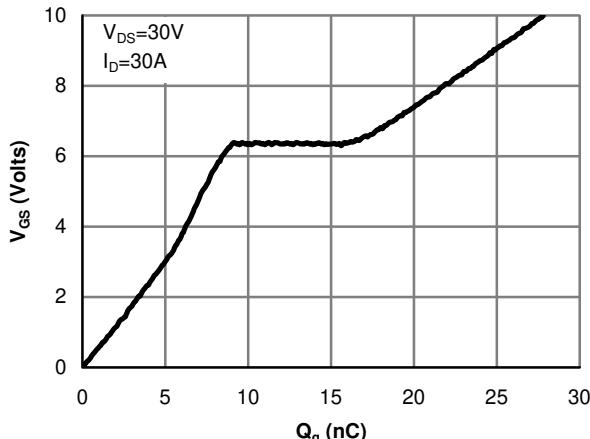
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


Figure 7: Gate-Charge Characteristics

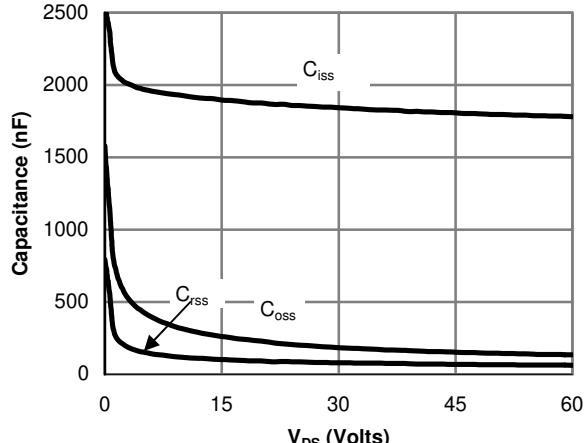


Figure 8: Capacitance Characteristics

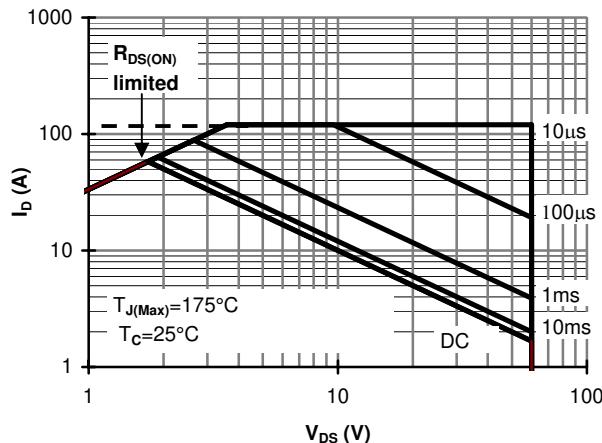


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

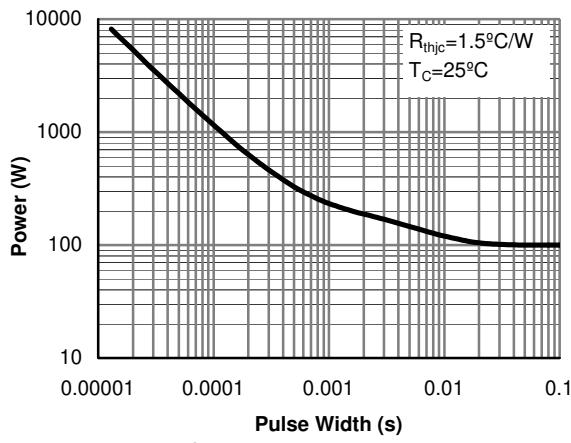


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

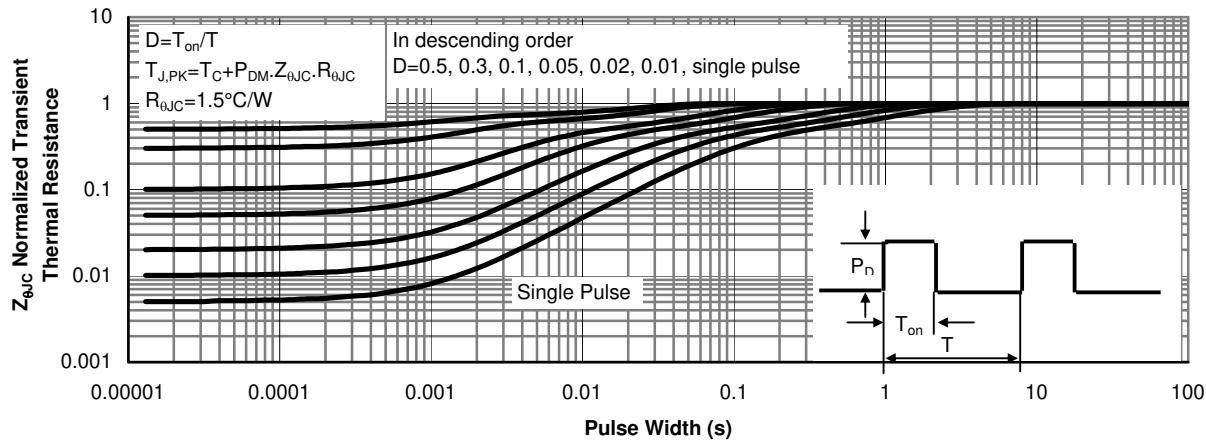


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

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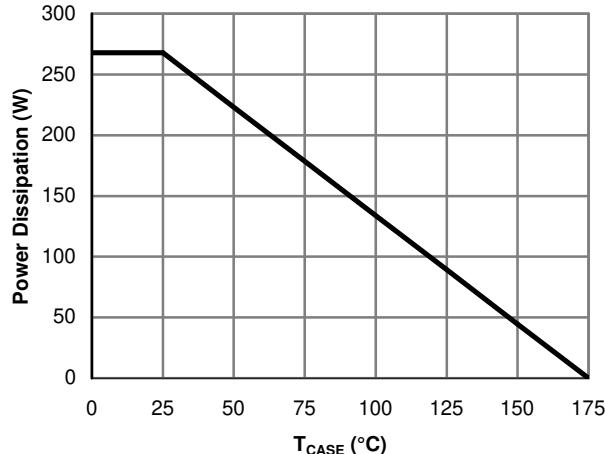
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

Figure 12: Power De-rating (Note B)

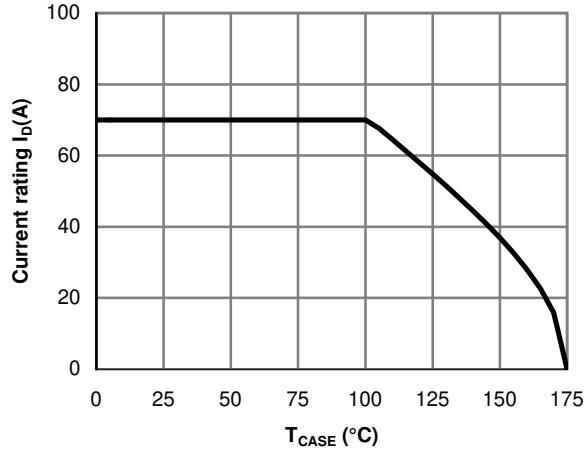


Figure 13: Current De-rating (Note B)

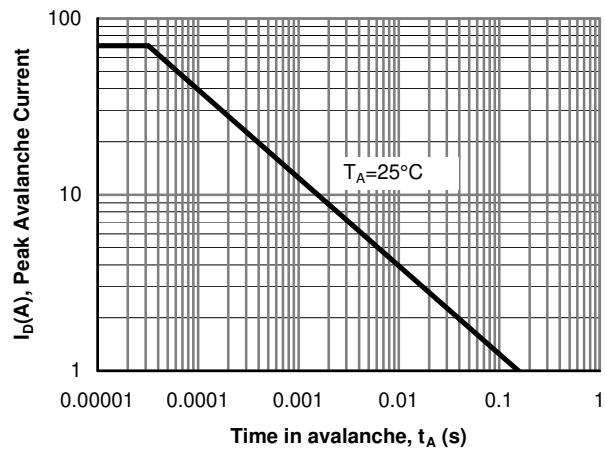


Figure 14: Single Pulse Avalanche capability